EXAMINER'S AMENDMENT

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This Examiner's Amendment is supplemental to the Examiner's Amendment dated 3/24/2010. In that action, amended claim 19 did not appear in its entirety. This action is intended to correct claim 19.

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Edward Machado on 3/12/2010.

The application has been amended as follows:

Claim 19 shall be entered as follows: A patterning method, comprising: applying an auxiliary layer to a carrier material; applying a mask layer to the auxiliary layer prior to a production of a cutout having a first side and a second side opposite the first side; patterning the mask layer with a lithographic method; patterning the auxiliary layer and the carrier material with the production of the cutout in accordance with the cutout; producing the cutout in the auxiliary layer and the carrier material in accordance with the mask layer; modifying the cutout in a region of the auxiliary layer by isotropic etch-back to form a modified cutout, where the cutout in a region of the carrier material is not modified or not modified to an extent of the region of the auxiliary layer; forming at least one layer in an expanded the modified cutout; filling the modified cutout having the at least one layer with a filling material; removing the

auxiliary layer after filling; and patterning the carrier material on the first side and the second side by using the filling material as a mask.

Claim 29 shall be entered as follows: The method of claim 24, further comprising: oxidizing the semiconductor material in [[the]] a region between the cutout and [[the]] a further cutout.

Claims 25 and 30-33 shall be cancelled.

Claim 36 shall be entered as follows: The method of claim [[25]] 19, where filling comprises filling with an electrically insulating layer and an electrically conductive layer.

Drawings

The objection to the drawings has been withdrawn, since the drawings do show the step of producing at least one further cutout in FIG. 2C.

Reasons for Allowance

The following is an examiner's statement of reasons for allowance:

Applicant has amended independent claim 19 to include the limitations of now cancelled claim 25, which was previously indicated as being allowable in the office action dated 7/30/2009.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to DANIEL LUKE whose telephone number is (571)270-1569. The examiner can normally be reached on Monday through Friday 8:30 a.m. to 5:00 p.m. EST.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Matthew Landau can be reached on (571) 272-1731. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/D. L./ Examiner, Art Unit 2813 5/20/2010 /Matthew C. Landau/ Supervisory Patent Examiner, Art Unit 2813